

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

247456US2SRD

SERIAL NO.

New Application

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Keitaro SHIGENAKA, et al.

FILING DATE

Herewith

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
CS	AO	9-284651	10/31/97	Japan		x
CS	AP	9-284561	10/31/97	Japan		x
CS	AQ	2002-286552	10/03/02	Japan (Corresponding to US Patent Application Serial Number 10/106,787)		x
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	X. GU, et al., "On-Chip Compensation of Self-Heating Effects in Microbolometer Infrared Detector Arrays", SENSORS AND ACTUATORS A, Vol. 69, 1998, pgs. 92-96				
	AX					
	AY					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Date Considered

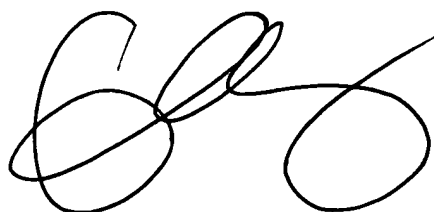
3/6/06

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF RELATED CASES

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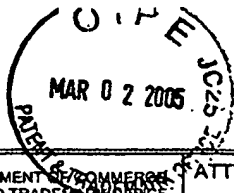
<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
221314US2 TTRD	10/106,787	03/27/02	IIDA et al.



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Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

247456US2SRD

SERIAL NO.

10753,386

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Keitaro SHIGENAKA, et al.

FILING DATE

January 9, 2004

GROUP

2878

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
CS	AO	2002-310783	10/23/2002	JAPAN		X
CS	AP	10-318843	12/04/1998	JAPAN		X
CS	AQ	7-35619	02/07/1995	JAPAN		X
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

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Date Considered

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